

## Supporting Information

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In Situ Exfoliation Method of Large-Area 2D Materials

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# Supplementary Information: In situ exfoliation method of large-area 2D materials

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# Characterization of WSe<sub>2</sub> on Au(111) substrate

WSe<sub>2</sub> was exfoliated onto an Au(111) single crystal using the KISS method. Optical microscopy and atomic force microscopy (AFM) data for this single-layer WSe<sub>2</sub> flake was shown in Figure 1 of the main text. Further characterization done on this flake is shown in supplementary Figure S1, while a large-scale AFM image for the same WSe<sub>2</sub>/Au(111) is shown in supplementary Figure S2. Low-Energy Electron Diffraction (LEED) data, Figure S1a, confirm the presence of only one WSe<sub>2</sub> domain, which is rotated 13° relative to the underlying Au(111) substrate. Angle-Resolved Photoemission Spectroscopy (ARPES) data taken around the high-symmetry point  $\bar{\Gamma}$ , Figure S1b (left), show the presence of WSe<sub>2</sub> states and Au surface state. The sample is a mixture of a single layer (SL) with a bilayer (BL) contribution, as indicated by the presence of two WSe<sub>2</sub> bands at  $\bar{\Gamma}$ . ARPES data taken around the  $\bar{K}$  point, Figure S1b (right), show the spin-split valence band (VB) of WSe<sub>2</sub>, with a splitting of approximately 440 meV. Bands arising from Au *sp* orbitals are also visible and intersect with the WSe<sub>2</sub> VB states.

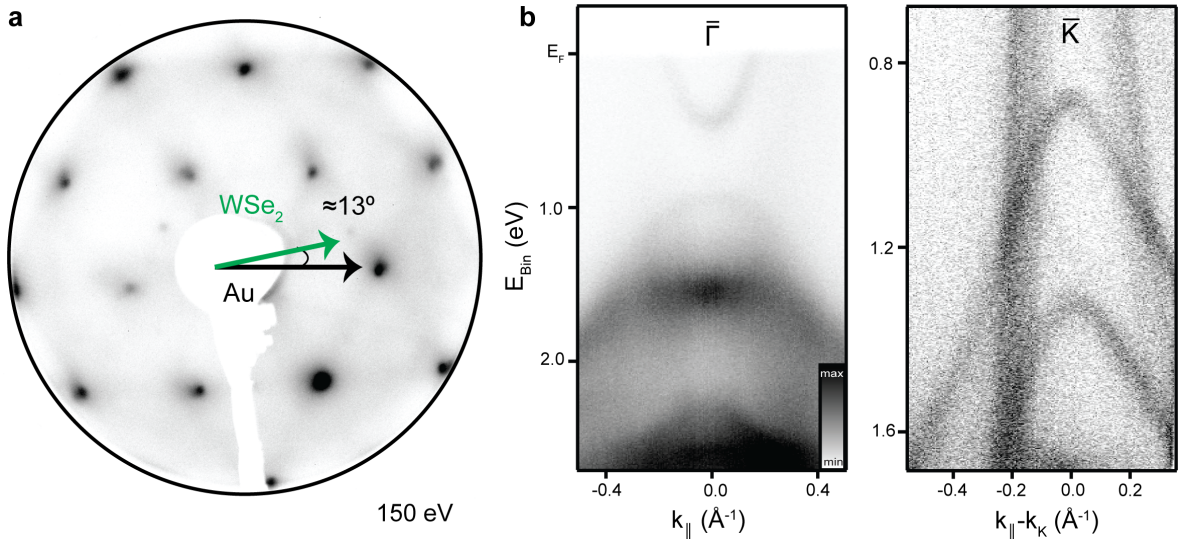


Figure S 1: WSe<sub>2</sub> on Au(111). **a** LEED image showing single crystal WSe<sub>2</sub> rotated 13° with respect to the underlying Au(111). The black arrow indicates Au, while the green arrow indicates the WSe<sub>2</sub> diffraction spot. **b** ARPES data of  $\bar{\Gamma}$  (left) and  $\bar{K}$  point (right). The sample is a single layer (SL) with a bilayer (BL) contribution.

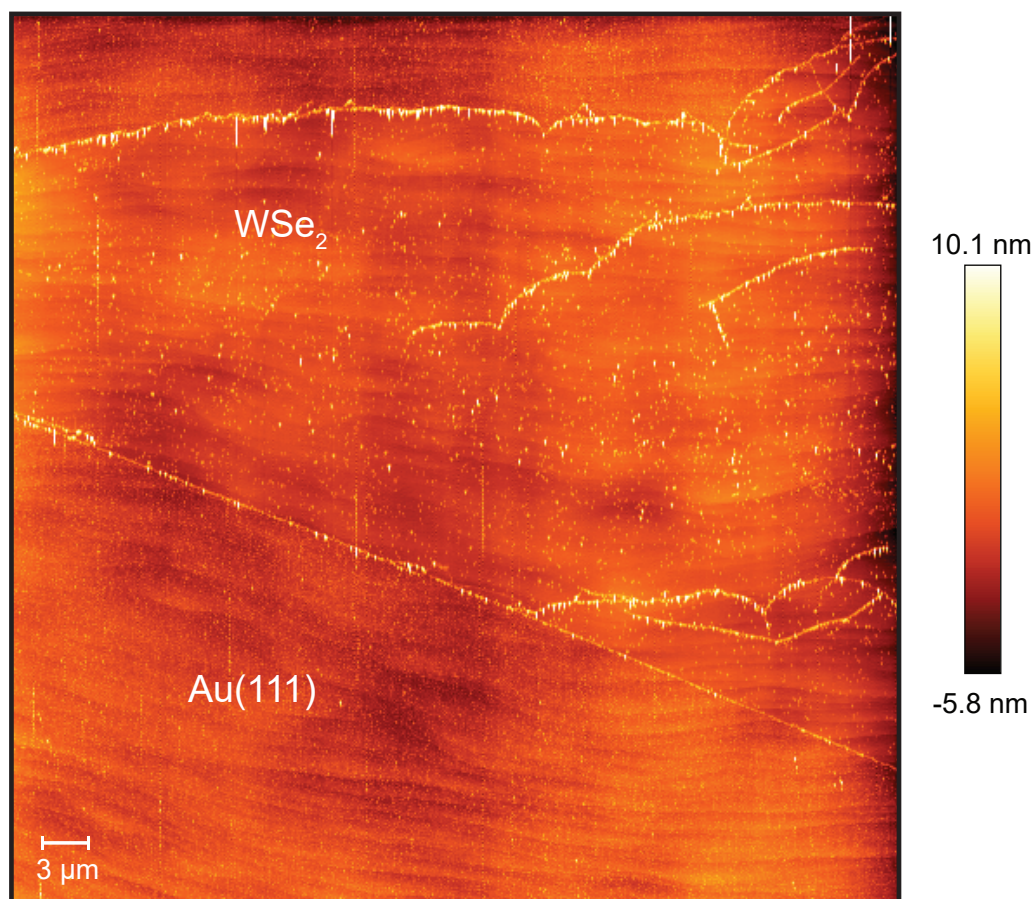


Figure S 2: Large scale AFM image of WSe<sub>2</sub> on Au(111).

## Monolayer-bilayer mix of MoS<sub>2</sub> on Ag(111) substrate

MoS<sub>2</sub> was exfoliated by the KISS method onto Ag(111), see Figure S3. Unlike other samples shown in the main text and supplementary information, this sample consists predominantly of BL regions. Optical microscopy, Figure S3a, shows that this sample is a mix of SL and BL, with smaller bulk regions present at the edges of some flakes. ARPES data, Figure S3b, show silver states (SS, *sp*-bands) coexisting with the MoS<sub>2</sub> bands. The VB maximum (VBM) for this sample is located at the  $\bar{\Gamma}$  point, as expected for a BL. The spin-splitting of states at  $\bar{K}$  is approximately 150 meV, as expected for MoS<sub>2</sub> on Ag.

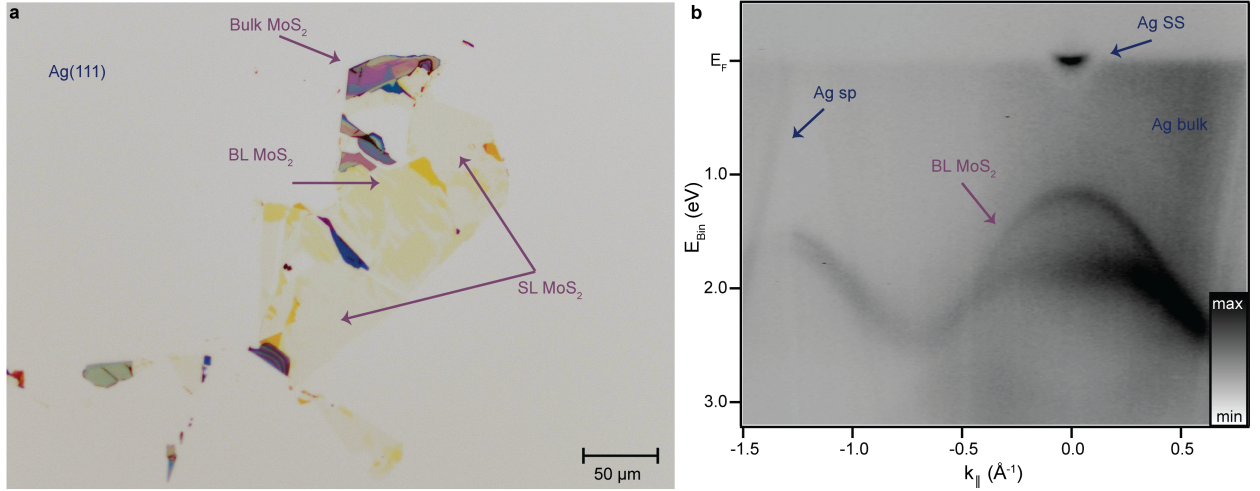


Figure S 3: Bilayer MoS<sub>2</sub> on Ag(111). **a** Optical microscopy image with SL, BL and bulk MoS<sub>2</sub> regions indicated. **b** ARPES data showing MoS<sub>2</sub> along the  $\bar{\Gamma}$ - $\bar{K}$  direction. Two bands are visible at the  $\bar{\Gamma}$  point, confirming that the sample is predominantly a BL.

## Fermi surface of WTe<sub>2</sub> on Ag(111) substrate

KISS-exfoliated flakes of WTe<sub>2</sub> on Ag(111) show 2D and bulk-like (3D) character in its energy dispersion. However, both regions show only a single domain, as seen in the Fermi surface (FS) maps of both regions. Figure S4 shows FS maps of WTe<sub>2</sub> on Ag(111), focusing on 2D (S4a) and bulk (S4b) regions. In both cases, only a single FS is visible, confirming that the exfoliated WTe<sub>2</sub> flake is single-crystal and has only one domain.

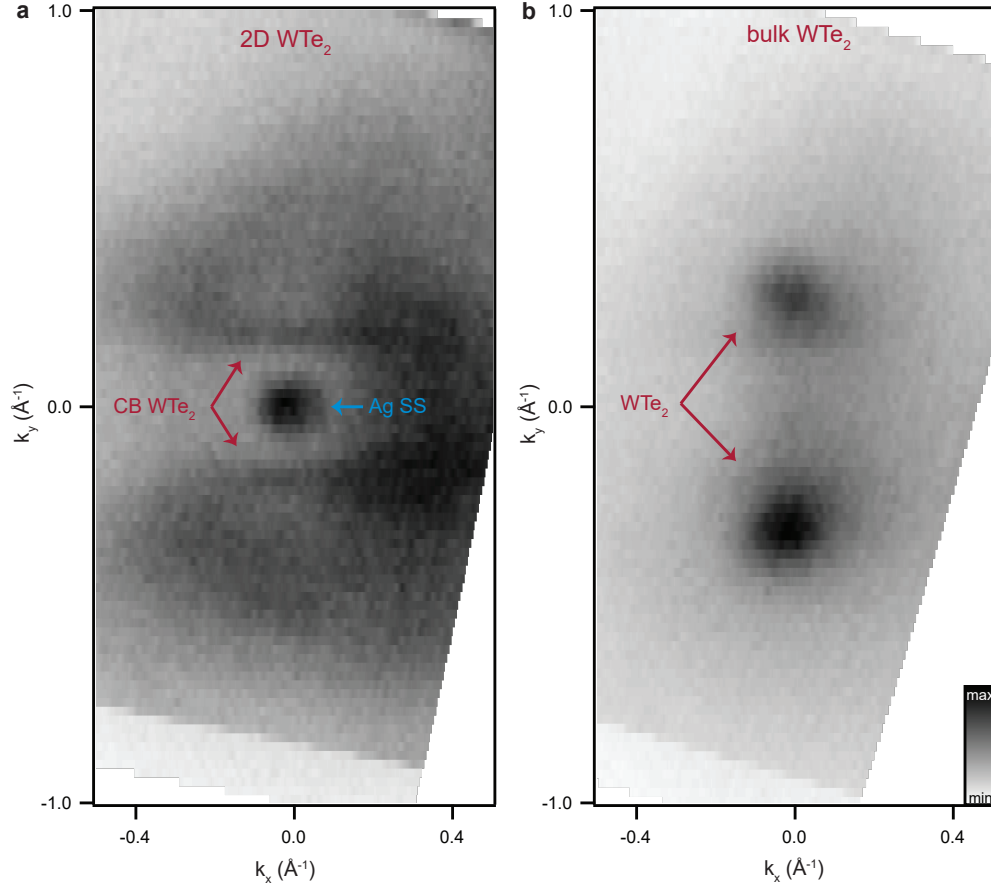


Figure S 4: Fermi surface of WTe<sub>2</sub> on Ag(111). **a** 2D WTe<sub>2</sub> with WTe<sub>2</sub> conduction band (CB) and Ag surface state (SS) indicated with arrows. **b** Bulk-like WTe<sub>2</sub>, WTe<sub>2</sub> states are indicated by arrows. In both cases, the Fermi surface shows only a single domain.

## Spatial mapping in the valence band region of MoS<sub>2</sub> on Ag(111)

KISS-exfoliated flakes were located on the substrate by ARPES raster-mapping focusing on the signal originating from core-levels or valence bands. An example of such a map is shown in Figure S5 for MoS<sub>2</sub> on Ag(111). Figure S5a shows a real-space map of the sample, with measurement locations for SL and BL MoS<sub>2</sub>, clean Ag, and the Ta sample holder indicated by colored stars. Figure S5b shows SL MoS<sub>2</sub>, and Figure S5c shows BL MoS<sub>2</sub> states at  $\bar{\Gamma}$ . The data was recorded on 2 different flakes, as seen in Figure S5a. Figure S5d shows clean Ag substrate, where no MoS<sub>2</sub> is exfoliated, while Figure S5e shows states coming from the Ta sample holder on which the Ag(111) substrate was mounted. The intensity in Figure S5a stems from the binding energy region marked with a black square in Figure S5c, where a SL MoS<sub>2</sub> band is expected.

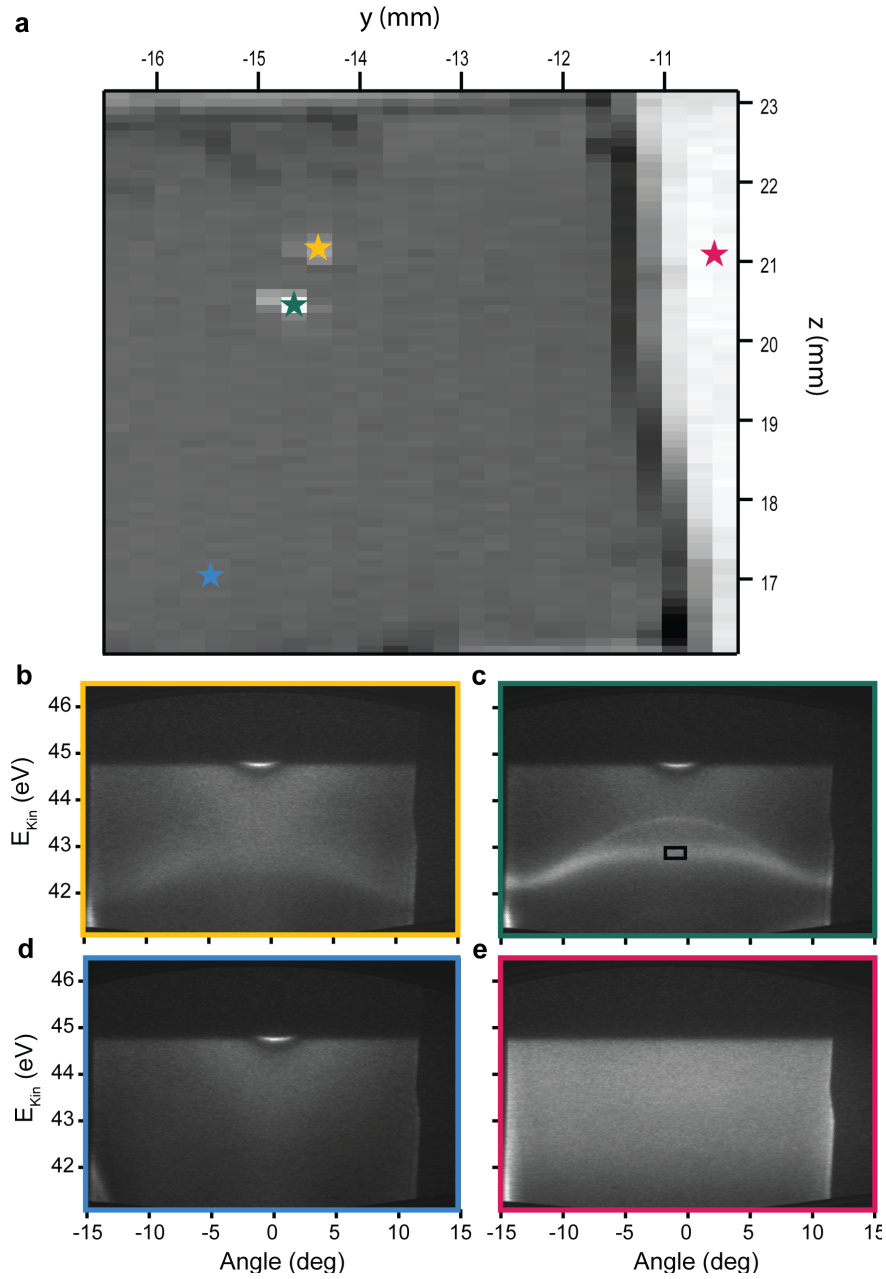


Figure S 5: An example of a spatial map used to locate KISS-exfoliated MoS<sub>2</sub> on Ag(111). **a** Spatial map showing 2 flakes of MoS<sub>2</sub> on the Ag(111). The colored stars mark the locations where the band structures in **b-e** were measured. **b** SL MoS<sub>2</sub>/Ag(111), **c** BL MoS<sub>2</sub>/Ag(111), **d** Ag surface state, with no MoS<sub>2</sub> states visible and **e** Ta sample plate. The frame colors match the stars indicating the location on the spatial map where the data is recorded. The black square in **c** shows the region from which the intensity for the real space map in **a** is captured.

## Sample holders used for *in situ* exfoliation

Exemplary sample holders used for *in situ* exfoliation are shown in figure S6. While the majority of the *in situ* exfoliation was done with spring-loaded holders (Figure S6 **b,c**), it is also possible to do with holders without a spring (Figure S6 **a**). Particular design differs based on the holders in use at the particular system, but it is generally very adaptable. The springs that were used in the experiments had the maximal load of 2.57 N, and the force during the KISS-exfoliation is measured to be 2.45 N.

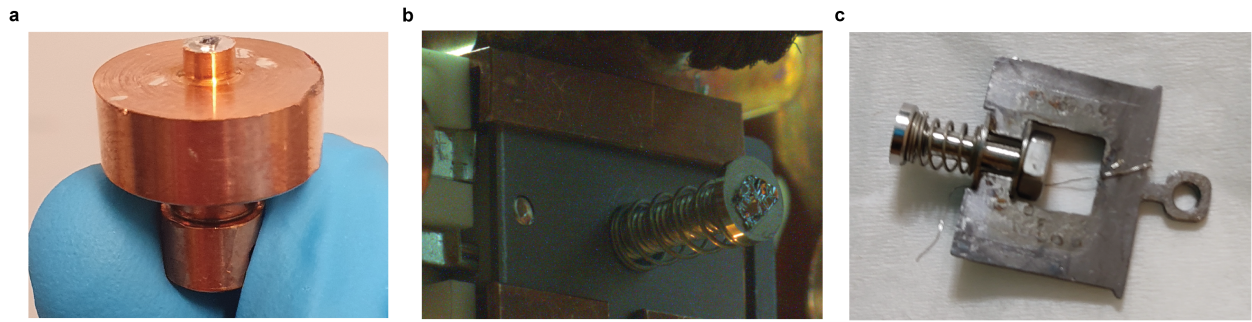


Figure S 6: Photographs of various sample plates used in KISS-exfoliation. Design differs slightly depending on the type of sample plate that is in use. **a** Sample plate used at the BALTAZAR facility without a loaded spring. Spring-loaded sample plate adapted for **b** home built sample holder of the SGM3 beamline and **c** for flag-type sample holder.

# AFM analysis of substrates and 2D materials morphology

We have performed AFM measurements on three different types of metallic substrates used in this work, Figure S7, and acquired optical images of typical surfaces obtained on layered materials by UHV-cleaving, Figure S8, in order to determine the role of substrate and crystal surface flatness on the UHV exfoliation success. Surface roughness analysis shows that Au(111)/mica has a more rough surface, average roughness 2.7 nm, compared to the Au(111) single crystal (1.8 nm) and Ag(111)/mica (1.4 nm). However, it is more likely that the uneven surface of UHV-cleaved crystals, clearly seen in the Figure S8, has much higher role on the success of the UHV-exfoliation, and size of the obtained flakes, as it will have higher influence on the contact quality.

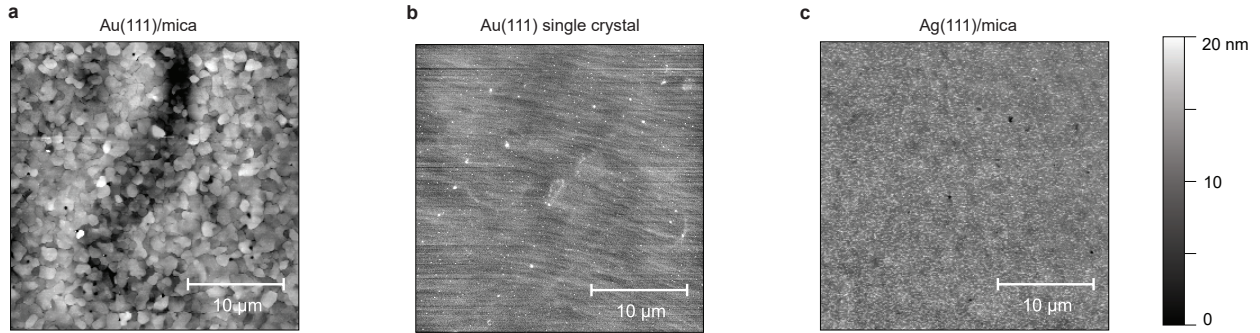


Figure S 7: In-air AFM images of UHV-cleaned substrates: Au(111)/mica, Au(111), Ag(111)/mica in **a-c**. The average roughness is 2.7 nm, 1.8 nm and 1.4 nm, respectively.

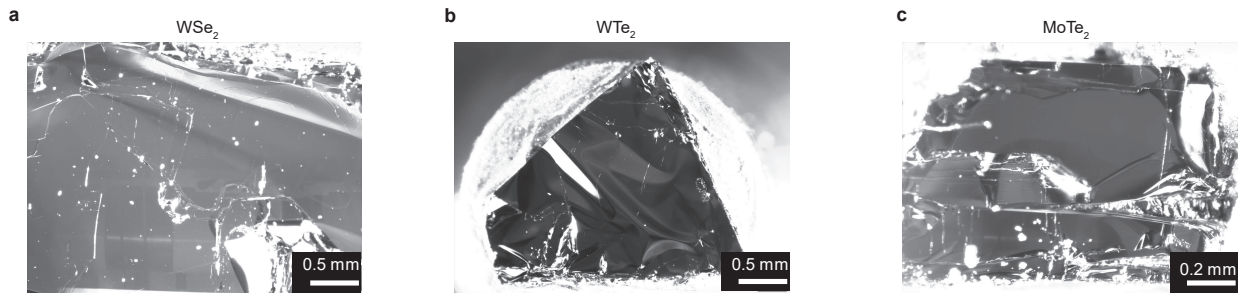


Figure S 8: Optical images of UHV-cleaved 2D materials: WSe<sub>2</sub>, WTe<sub>2</sub>, MoTe<sub>2</sub> in **a-c**.

## Large scale optical images of samples prepared with *in situ* exfoliation

Large scale images for UHV exfoliated flakes shown in the main text are shown in Figure S9, Majority of the exfoliated flakes are very thin, with thicker regions typically at the flake edges.

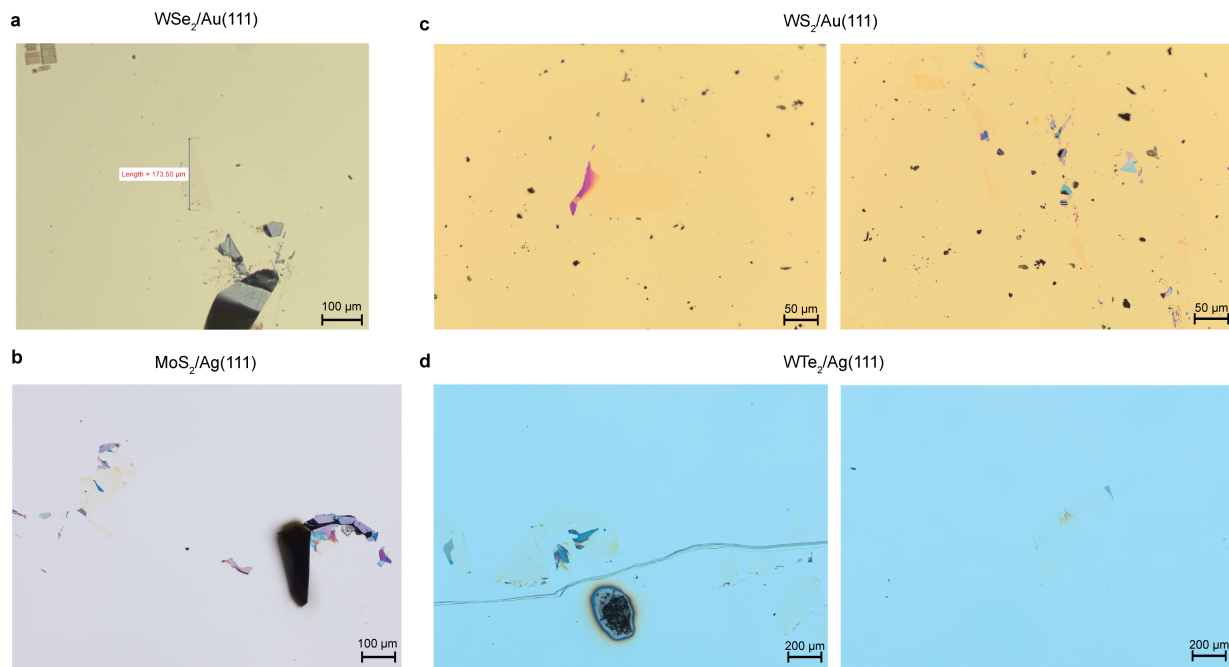


Figure S 9: Larger scale images for data presented in the main text. **a** WSe<sub>2</sub>/Au(111) single crystal, **b** MoS<sub>2</sub>/Ag(111)/mica, **c** Two different spots of WS<sub>2</sub>/Au(111)/mica and **d** Two different spots of WTe<sub>2</sub>/Ag(111)/mica.